

Abstract

The present invention relates to a communication circuit arrangement (1) providing a testing functionality. A switch (10) couples internal circuit nodes of a transmission path (2) and a receiver path (3) of an interface communication circuit (1), thereby providing a test signal loop. By feeding a test signal (A) into an input terminal (11) of a transmission path (2) and comparing this original signal (A) with a received signal (B) from output terminal (14) of receiver path (3), functional faults of the circuit are revealed at early development stages. The test method is preferably applicable in communication devices.

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